

Maximum Ratings (@T_A = +25°C, unless otherwise specified.)

Characteristic			Symbol	Value	Unit
Drain-Source Voltage		V _{DSS}	40	V	
Gate-Source Voltage (Note 5)		(Note 5)	V _{GS}	±20	V
		(Notes 7)		7.1	
Continuous Drain Current	$V_{GS} = 10V$	$T_A = +70^{\circ}C \text{ (Notes 7)}$	I _D	5.7	Α
		(Notes 6)		5.4	
Pulsed Drain Current	$V_{GS} = 10V$	(Notes 8)	I _{DM}	28.0	А
Continuous Source Current (Body diode) (Notes 7)		(Notes 7)	Is	3.3	А
Pulsed Source Current (Body diode) (Notes 8)		I _{SM}	28.0	А	

Thermal Characteristics (@TA = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Unit		
	(Notes 6 & 9)		1.25 10.0	W mW/°C	
Power Dissipation Linear Derating Factor	(Notes 6 & 10)	P _D	1.8 14.3		
	(Notes 7 & 9)		2.14 17.2		
	(Notes 6 & 9)		100	°C/W	
Thermal Resistance, Junction to Ambient	(Notes 6 & 10)	$R_{ hetaJA}$	70		
	(Notes 7 & 9)		58		
Thermal Resistance, Junction to Lead	(Notes 9 & 11)	$R_{ heta JL}$	53		
Operating and Storage Temperature Range	T _J , T _{STG}	-55 to +150	°C		

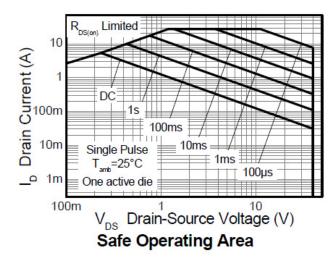
Notes:

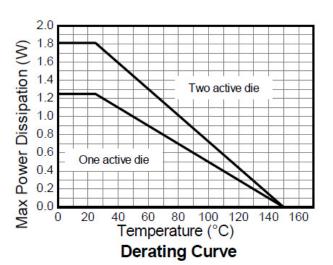
- 5. AEC-Q101 V_{GS} maximum is $\pm 16 \text{V}.$
- 6. For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions; the device is measured when operating in a steady-state condition.
- 7. Same as note (3), except the device is measured at $t \le 10$ sec.
- Same as note (3), except the device is pulsed with D = 0.02 and pulse width 300μs. The pulse current is limited by the maximum junction temperature.
 For a dual device with one active die.

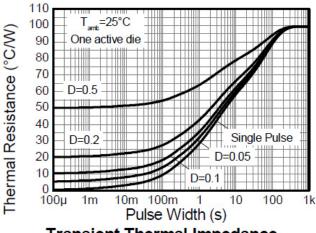
- 10. For a device with two active die running at equal power.11. Thermal resistance from junction to solder-point (at the end of the drain lead).

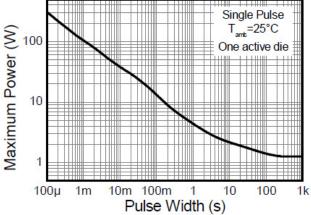


Thermal Characteristics









Transient Thermal Impedance

Pulse Power Dissipation



Electrical Characteristics (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	BV _{DSS}	40	_	_	V	$I_D = 250 \mu A, V_{GS} = 0 V$	
Zero Gate Voltage Drain Current	I _{DSS}		_	0.5	μA	$V_{DS} = 40V$, $V_{GS} = 0V$	
Gate-Source Leakage	I _{GSS}	_	_	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
ON CHARACTERISTICS							
Gate Threshold Voltage	V _{GS(th)}	1.0	_	3.0	٧	$I_D = 250\mu A,\ V_{DS} = V_{GS}$	
Static Drain-Source On-Resistance (Note 12)	D	_	0.017	0.027	Ω	$V_{GS} = 10V, I_D = 7A$	
Static Dialif-Source Off-Resistance (Note 12)	R _{DS(ON)}		0.031	0.047	(2	$V_{GS} = 4.5V, I_D = 6A$	
Forward Transconductance (Notes 12 & 13)	g _{fs}	_	22.8	_	S	$V_{DS} = 15V, I_{D} = 7A$	
Diode Forward Voltage (Note 12)	V_{SD}		0.86	1.1	V	$I_S = 7A$, $V_{GS} = 0V$	
Reverse recovery time (Note 13)	t _{rr}		12.1	_	ns	-I _S = 2.1A, di/dt = 100A/μs	
Reverse recovery charge (Note 13)	Q _{rr}	_	5.1	_	nC		
DYNAMIC CHARACTERISTICS (Note 13)							
Input Capacitance	C _{iss}		604	_	pF	V _{DS} = 20V, V _{GS} = 0V - f = 1MHz	
Output Capacitance	Coss	_	106	_	pF		
Reverse Transfer Capacitance	C _{rss}		59.6	_	pF		
Total Gate Charge (Note 14)	Qg	_	6.3	_	nC	V _{GS} = 4.5V	
Total Gate Charge Note 14)	Qg		12.9	_	nC	V _{DS} = 20V	
Gate-Source Charge Note 14)	Qgs		2.4	_	nC	$V_{GS} = 10V$ $I_D = 7A$	
Gate-Drain Charge Note 14)	Q _{gd}	_	3.3	_	nC		
Turn-On Delay Time Note 14)	t _{D(on)}	_	3.1	_	ns		
Turn-On Rise Time Note 14)	t _r	_	3.1	_	ns	$V_{DD} = 20V, V_{GS} = 10V$	
Turn-Off Delay Time (Note 14)	t _{D(off)}	_	15.4	—	ns	- , °	
Turn-Off Fall Time Note 14)	t _f	_	7.5	_	ns		

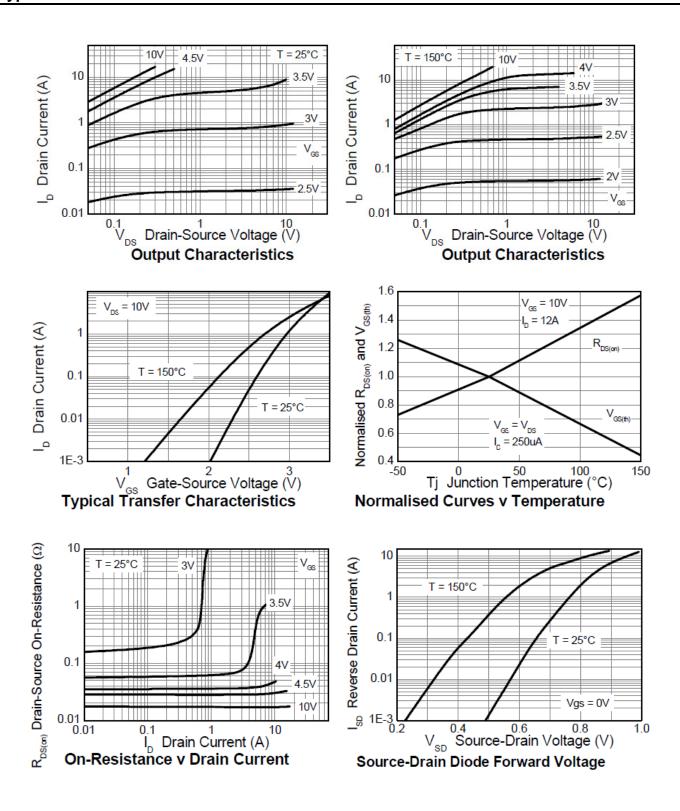
Notes:

^{12.} Measured under pulsed conditions. Pulse width ≤ 300µs; duty cycle ≤ 2%.
13. For design aid only, not subject to production testing.
14. Switching characteristics are independent of operating junction temperatures.



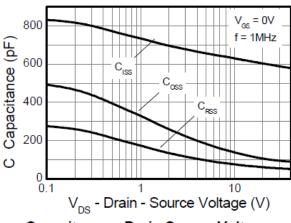


Typical Characteristics

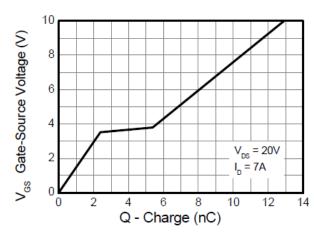




Typical Characteristics (cont.)

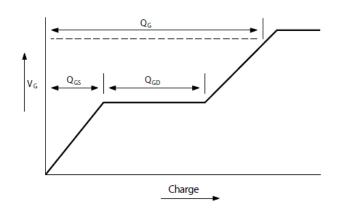


Capacitance v Drain-Source Voltage

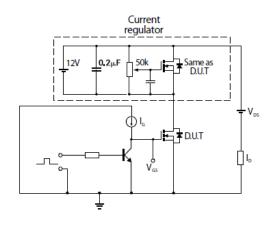


Gate-Source Voltage v Gate Charge

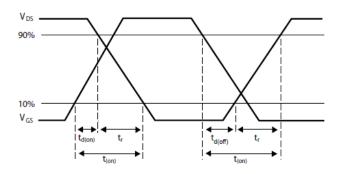
Test Circuits



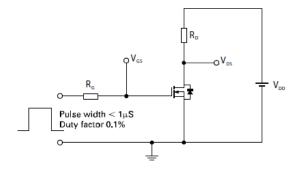
Basic gate charge waveform



Gate charge test circuit



Switching time waveforms

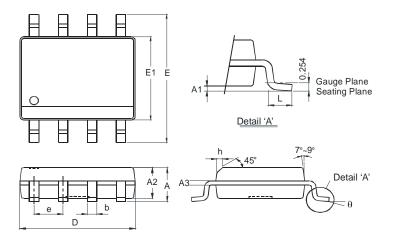


Switching time test circuit



Package Outline Dimensions

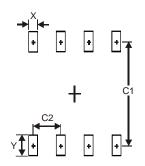
Please see AP02002 at http://www.diodes.com/datasheets/ap02002.pdf for latest version.



SO-8				
Dim	Min	Max		
Α	-	1.75		
A1	0.10	0.20		
A2	1.30	1.50		
A3	0.15	0.25		
b	0.3	0.5		
D	4.85	4.95		
Е	5.90	6.10		
E1	3.85	3.95		
е	1.27 Typ			
h	-	0.35		
L	0.62	0.82		
θ	0°	8°		
All Dimensions in mm				

Suggested Pad Layout

Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.



Dimensions	Value (in mm)
X	0.60
Υ	1.55
C1	5.4
C2	1.27





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